Announcement

PNS ON SEMICONDUCTOR DEVICES

The Department of Trade and Industry’s Bureau of Product Standards (DTI-BPS) informs the concerned sectors that the following standards have been adopted as PNS.

The DTI-BPS adopts these standards through the fast tract method.

- **PNS IEC 60749-20-1:2013** - Semiconductor devices - Mechanical and climatic test methods - Part 20-1: Handling, packing, labelling and shipping of surface-mount devices sensitive to the combined effect of moisture and soldering heat (IEC published 2009) ICS 31.080.01
- **PNS IEC 60749-20:2013** - Semiconductor devices - Mechanical and climatic test methods - Part 20: Resistance of plastic encapsulated SMDs to the combined effect of moisture and soldering heat (IEC published 2008) ICS 31.080.01
- **PNS IEC 60749-26:2013** - Semiconductor devices - Mechanical and climatic test methods - Part 26: Electrostatic discharge (ESD) sensitivity testing - Human body model (HBM) (IEC published 2013) ICS 31.080.01


Copies of the standard can be purchased from the BPS Standards Data Centre at 751.4736.